

Preface

This book contains the invited and contributed papers presented at the International Workshop on *Nanoscale Spectroscopy and Its Applications to Semiconductor Research* which was held in Trieste, December 11–14, 2000.

Nanostructured semiconductor materials with dimensions less than the de Broglie wavelength of electrons are expected to exhibit quite different electronic properties from those of common three-dimensional devices. The fabrication technologies for nanostructured devices have been developed only recently, and the electrical and optical properties of such nanostructures are still the subject of advanced research. However, classical spectroscopic techniques cannot be applied to these structures because their lateral resolution is not sufficient to resolve the structures.

Bearing that in mind, the workshop was aimed at comparing and discussing different approaches to spectroscopic microscopy, like electron beam probe spectroscopy, spectroscopic photoelectron microscopy, and scanning probe spectroscopy, in view of their application to nanostructured semiconductor materials and devices. In this respect, it was decided to collect the papers in homogeneous groups characterized by the spectroscopic technique employed, in order to better show the limits and possibilities of the different experimental approaches.

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G. Salviati
Workshop Chairman

Acronyms

CBED	Convergent Beam Electron Diffraction
CL	Cathodoluminescence
CTEM	Conventional Transmission Electron Microscopy
EELS	Electron Energy Loss Spectroscopy
ESD	Electron Stimulated Desorption
ESRF	European Synchrotron Radiation Facility
FA	Fluorescence Analysis
FEM	Field Emission Electron Microscopy
FTIR	Fourier Transform Infrared Spectroscopy
HBT	Hetero Bipolar Transistor
HEMT	High Electron Mobility Transistor
HOPG	Highly Oriented Pyrolytic Graphite
HRTEM	High Resolution Transmission Electron Microscopy
LEEM	Low Energy Electron Microscopy
MAES	Metastable-Atom Electron Spectroscopy
MEEM	Metastable Electron Emission Microscopy
MEM	Mirror Electron Microscopy
OBIC	Optical Beam Induced Current
PEEM	Photoemission Electron Microscopy
PES	Photoelectron Spectroscopy
PLI	Photoluminescence Imaging
REM	Reflection Electron Microscopy
RHEED	Reflection High Energy Electron Diffraction
SAM	Scanning Auger Microscopy
SCL	Spectrally Resolved Cathodoluminescence
SEAM	Scanning Electron Acoustic Microscopy
SEM	Scanning Electron Microscopy
SNOM	Scanning Near Field Optical Microscopy
SPEEM	Scanning Photoemission Electron Microscopy
SPELEEM	Spectroscopic Photoemission and Low Energy Electron Microscopy
SPEM	Scanning Photoelectron Microscopy
STEM	Scanning Transmission Electron Microscopy
STM	Scanning Tunneling Microscopy
STS	Scanning Tunneling Spectroscopy
STXM	Scanning Transmission X-ray Microscopy

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SXTM	Scanning X-ray Transmission Microscopy
TED	Transmission Electron Diffraction
TEM	Transmission Electron Microscopy
TXM	Transmission X-ray Microscopy
XMCD	X-ray Magnetic Circular Dichroism
XPEEM	X-ray Photoemission Electron Microscopy
XPLEEM	X-ray Photoemission and Low Energy Electron Microscopy
XPS	X-Ray Photoelectron Spectroscopy

List of Contributors

A. Armigliato

CNR Istituto LAMEL,
via P. Gobetti 101,
40129 Bologna, Italy
armiglia@lamel.bo.cnr.it

M. Bertolo

Sincrotrone Trieste,
S.S.14 Km 163.5,
Area Science Park,
34012 Basovizza–Trieste, Italy
michele.bertolo
@elettra.trieste.it

R. Cingolani

INFN Unita di Lecce,
Dipartimento di Ingegneria
dell’Innovazione,
Universita di Lecce,
via Arnesano,
73100 Lecce, Italy
roberto.cingolani@unile.it

M. Colocci

INFN Dipartimento di Fisica,
and LENS,
via Sansone 1,
50019 Sesto Fiorentino, Italy
colocci@fi.infn.it

A. Crottini

Physics Department,
Swiss Federal Institute of Technology
Lausanne,
1015 Lausanne-EPFL, Switzerland
Andrea.Crottini@alcatel.fr

S. Heun

Sincrotrone Trieste,
S.S.14 Km 163.5,
Area Science Park,
34012 Basovizza–Trieste, Italy
stefan.heun@elettra.trieste.it

S.-W. Hla

Department of Physics
and Astronomy,
Ohio University, Athens,
OH 45701, USA
hla@helios.phy.ohiou.edu

M. Ivanda

Rudjer Boskovic Institute,
P.O. Box 180,
10002 Zagreb, Croatia
ivanda@rudjer.irb.hr

H. Iwasaki

The Institute of Scientific
and Industrial Research,
Osaka University,
8-1 Mihogaoka,
Ibaraki 567-0047, Japan
iwasaki
@isir2.sanken.osaka-u.ac.jp

T.K. Johal

INFN Unita di Lecce,
Dipartimento di Ingegneria
dell’Innovazione,
Universita di Lecce,
via Arnesano,
73100 Lecce, Italy
johal@axpmat.unile.it

K. Kanisawa

NTT Basic Research Laboratories,
3-1, Morinosato Wakamiya, Atsugi,
Kanagawa, 243-0198, Japan
kani@will.brl.ntt.co.jp

B. Kaulich

Sincrotrone Trieste,
S.S.14 Km 163.5,
Area Science Park,
34012 Basovizza–Trieste, Italy
burkhard.kaulich
@elettra.trieste.it

T. Kinoshita

Synchrotron Radiation Laboratory,
Institute for Solid-State Physics,
University of Tokyo,
KEK-PF, Oho1-1,
Tsukuba 305-0801, Japan
toyohiko@issp.u-tokyo.ac.jp

M. Kiskinova

Sincrotrone Trieste,
S.S.14 Km 163.5,
Area Science Park,
34012 Basovizza–Trieste, Italy
maya.kiskinova
@elettra.trieste.it

O. Martínez

Dpto. Física de la Materia
Condensada, ETSII,
47011 Valladolid, Spain
oscar@fmc.uva.es

L. Ottaviano

INFN Unit and Physics Department
University of L'Aquila,
Via Vetoio 10,
67010 Coppito L'Aquila, Italy
luca.ottaviano@aquila.infn.it

K.C. Prince

Sincrotrone Trieste,
S.S.14 Km 163.5,

Area Science Park,
34012 Basovizza–Trieste, Italy
kevin.prince@elettra.trieste.it

F. Rosei

Dipartimento di Fisica and Unità
INFN,
Università di Roma Tor Vergata,
Via della Ricerca Scientifica n. 1,
00133 Roma, Italy
ico@ifa.au.dk

M. Sakurai

The Institute of Physical
and Chemical Research (RIKEN),
Hirosawa 2-1, Wako-shi,
Saitama 351-0198, Japan
msakurai@postman.riken.go.jp

G. Salviati

CNR-MASPEC,
Parco Area delle Scienze 37a,
43010 Parma, Italy
salviati@maspec.bo.cnr.it

T. Sekiguchi

Nanomaterials Laboratory,
National Institute for Materials
Science,
Sengen 1-2-1,
Tsukuba 305-0047, Japan
SEKIGUCHI.Takashi@nims.go.jp

J.P. Singh

Nuclear Science Centre,
Aruna Asaf Ali Marg,
New Delhi 110 067, India
singhj@rpi.edu

N. Ueno

Department of Materials Technology,
Faculty of Engineering,
Chiba University, Inage-ku,
Chiba 263-8522, Japan
uenon@xtal.tf.chiba-u.ac.jp

S. Ushioda

Research Institute of Electrical
Communication,
Tohoku University, and CREST,
Japan Science and Technology
Corporation,
Sendai 980-8577, Japan
ushioda
@ushioda.riec.tohoku.ac.jp

R. Vašina

Delong Instruments,
Bulharská 48,
Brno, CZ-612 00, Czech Republic
radek.vasina@dicomps.com

Y. Watanabe

NTT Basic Research Laboratories,

3-1, Morinosato Wakamiya, Atsugi,
Kanagawa, 243-0198, Japan
wata@will.brl.ntt.co.jp

K. Yagi

Physics Department,
Tokyo Institute of Technology,
Oh-okayama, Meguro,
Tokyo 152-8551 Japan
kyagi@surface.phys.titech.ac.jp

N. Yamamoto

Department of Physics,
Tokyo Institute of Technology,
Meguro-ku Tokyo 152-8551, Japan
nyamamot
@surface.phys.titech.ac.jp